

# FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16472

Generic Copy

### 11-May-2010

**<u>TITLE</u>**: Qualification of Nantong-Fujitsu Microelectronics for Assembly/Test of TO-247 Ultrafast Rectifiers.

### PROPOSED FIRST SHIP DATE: 11-Aug-2010

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Assembly & Test Site

### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Mike Schager at mike.schager@onsemi.com

<u>SAMPLES</u>: Contact your local ON Semiconductor Sales Office or Mike Schager at <u>mike.schager@onsemi.com</u>

#### ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Laura Rivers at laura.rivers@onsemi.com

#### NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

### DESCRIPTION AND PURPOSE:

This FPCN16472 (a follow up to FPCN16371) announces the planned capacity expansion of ON Semiconductor's assembly and test operations of TO-247 Discrete packaged products, currently built at the PSI Manila facility, to Nantong-Fujitsu's China facility. Upon the expiration of this FPCN, these Ultrafast Rectifier devices may be processed at either location. The Nantong-Fujitsu facility is currently used to manufacture ON's TO-220AB, TO-220AC, I2PAK, TO-247 & DPAK devices, and is ISO/TS 16949:2002 certified.

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### **RELIABILITY DATA SUMMARY:**

### Reliability Test Results:

Package: TO-247 Qualification Vehicles: MJW21195G MJW21196G MBR40H100WTG MBR7030WTG MUR3060WTG

MJW21195G			
Test:	Conditions:	Interval:	Results
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/77
H3TRB+PC	Ta=85C RH=85%	1008 hrs	0/77
	bias=80% rated V or100V Max		
IOL+PC	Ta=25C, Delta TJ = 100 C,	8572 cyc	0/77
	Ton/off = 3.5 min.		
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/77
RSH	Ta=260C, 10 sec dwell		0/30

MJW21196G

Test:	Conditions:	Interval:	Results	
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/77	
H3TRB+PC	Ta=85C RH=85%	1008 hrs	0/77	
	bias=80% rated V or100V Max			
IOL+PC	Ta=25C, Delta TJ = 100 C,	8572 cyc	0/77	
	Ton/off = 3.5 min.			
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/77	
RSH	Ta=260C, 10 sec dwell		0/30	
MBR40H100W1G				
Test:	Conditions:	Interval:	Results	

Test.	Conditions.	interval.	Results
Autoclave+PC	Ta=121C RH=100% ~15 psig	96 hrs	0/154
H3TRB+PC	Ta=85C RH=85%	1008 hrs	0/154
	bias=80% rated V or100V Max		

MBR7030WTG Test: Autoclave+PC TC+PC RSH	Conditions: Ta=121C RH=100% ~15 psig Ta= -65 C to 150 C Ta=260C, 10 sec dwell	Interval: 96 hrs 1000 cyc	Results 0/154 0/154 0/60
MUR3060WTG Test: Autoclave+PC H3TRB+PC	Conditions: Ta=121C RH=100% ~15 psig Ta=85C RH=85% bias=80% rated V or100V Max	Interval: 96 hrs 1008 hrs	Results 0/154 0/154

Issue Date: 11-May-2010

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### **ELECTRICAL CHARACTERISTIC SUMMARY:**

There are no changes in electrical characteristics; and product performance meets datasheet specifications. Characterization data is available upon request.

### **CHANGED PART IDENTIFICATION:**

Product from Nantong-Fujitsu will be identified by NF site code marking.

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List of affected General Parts:

MUR3020WTG MUR3040WTG MUR3060WTG